

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|--------|--|---|------------------|---------|------------------|
| S5 | 67018 | electrical adj characteristic | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:17 |
| S6 | 79540 | pattern same wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:18 |
| S7 | 113525 | (initial first) with design | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:19 |
| S8 | 29556 | layout same generat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:19 |
| S9 | 30 | S5 and S6 and S7 and S8 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:20 |
| S10 | 22 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:28 |
| S11 | 21 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:28 |
| S12 | 20 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:29 |

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| S13 | 20 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:29 |
| S14 | 20 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion and size | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:30 |
| S15 | 17 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion and size and adjacent | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:33 |
| S16 | 0 | S5 and S6 and S7 and S8 and simulat\$3 and modif\$5 and structure and process with variation and portion and size and adjacent and intensity | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/13 19:33 |
| S17 | 16 | layout adj generat\$3 and modif\$7 with design and electrical adj characteristic | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 13:28 |
| S18 | 6 | layout adj generat\$3 and modif\$7 with design same electrical adj characteristic | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 13:28 |
| S19 | 1 | (actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:29 |
| S20 | 0 | (actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design) and layout with generat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:28 |

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| S21 | 0 | (actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design) and layout same generat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:29 |
| S22 | 0 | (actual desired) with characteristic same match\$3 same modif\$7 same (netlist initial adj3 design) and (physical layout) same generat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:29 |
| S23 | 14540 | layout with generat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:30 |
| S24 | 67018 | electrical adj characteristic | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:30 |
| S25 | 3088 | simulat\$3 same structure same pattern | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:31 |
| S26 | 169262 | (actual desired) same (design characteristic) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:32 |
| S27 | 17024 | (actual desired) same (design characteristic) same modif\$7 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:33 |
| S28 | 9 | S23 and S24 and S25 and S27 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:44 |

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| S29 | 190 | slope near4 edge with intensity | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:47 |
| S30 | 0 | S28 and S29 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:47 |
| S31 | 22 | process adj2 variation same slope and layout | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:50 |
| S32 | 0 | S31 and S28 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:48 |
| S33 | 20 | process adj2 variation same slope and layout and feature | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:58 |
| S34 | 3 | S23 and S33 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:53 |
| S35 | 1 | S23 and S33 and S24 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:53 |
| S36 | 9 | S33 and S24 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 14:55 |

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| S37 | 344 | slope with (edge intensity) same (larger smaller) same variation | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 15:00 |
| S38 | 0 | S37 and S23 and S24 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/14 15:02 |
| S43 | 67024 | electrical adj characteristic | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:01 |
| S44 | 8021 | electrical adj characteristic and model\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:01 |
| S45 | 60 | electrical adj characteristic same layout same simulat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:02 |
| S46 | 37 | electrical adj characteristic same layout same simulat\$3 and pattern | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:02 |
| S47 | 27 | electrical adj characteristic same layout same simulat\$3 and pattern and variation | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:03 |
| S48 | 26 | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:03 |

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| S49 | 20 | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:03 |
| S50 | 17 | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:03 |
| S51 | 17 | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:04 |
| S52 | 13 | electrical adj characteristic same layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5 with layout | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:10 |
| S53 | 56 | electrical adj characteristic and layout same simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5 with layout | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:14 |
| S54 | 63 | electrical adj characteristic and layout and simulat\$3 and pattern and variation and structure and wafer and modif\$5 and generat\$5 with layout | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:27 |
| S55 | 1342 | intensity same edge same slope | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:29 |
| S56 | 0 | S54 and S55 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:28 |

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| S57 | 1797 | intensity same edge same (derivative slope) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:29 |
| S58 | 0 | S54 and S57 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:29 |
| S59 | 1895 | intensity same edge same (derivative slope logarith\$2) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:30 |
| S60 | 0 | S54 and S59 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:39 |
| S61 | 1226 | 716/2.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:39 |
| S62 | 47 | 716/2.ccls. and variation and S43 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:52 |
| S63 | 8 | 716/2.ccls. and variation and S43 and pattern and wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:40 |
| S64 | 7 | layout adj simulation adj tool | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:53 |

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| S65 | 5 | layout adj simulation adj tool and electrical adj characteristic | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:54 |
| S66 | 2 | layout adj simulation adj tool and electrical adj characteristic and variation | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:55 |
| S67 | 486 | layout and simulat\$3 and electrical adj characteristic and variation and pattern | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:55 |
| S68 | 212 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:55 |
| S69 | 58 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:56 |
| S70 | 58 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:56 |
| S71 | 58 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:56 |
| S72 | 57 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:58 |

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| S73 | 0 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 and netlist | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:57 |
| S74 | 0 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 and (HDL netlist) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:57 |
| S75 | 4 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and slope and structure and generat\$3 and modif\$5 and wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 10:58 |
| S76 | 13 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and (derivative slope) and structure and generat\$3 and modif\$5 and wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 11:03 |
| S77 | 7 | layout and simulat\$3 and electrical adj characteristic and variation and pattern and intensity and (derivative slope) same position and structure and generat\$3 and modif\$5 and wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 11:03 |
| S78 | 960 | (slope derivative) same (larger small greater less more) same edge same intensity | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 13:39 |
| S79 | 27 | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 13:42 |
| S80 | 20 | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 13:42 |

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| S81 | 20 | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation and process | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 13:45 |
| S82 | 2 | (slope derivative) same (larger small greater less more) same edge same intensity and pattern and wafer and layout and variation and process and electrical adj characteristic | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/04/16 13:43 |